

<b>Notice of References Cited</b>		Application/Control No. 10/075,834	Applicant(s)/Patent Under Reexamination SARFERT, CHRISTEL	
		Examiner Toan M Le	Art Unit 2863	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-5,349,540	09-1994	Birkle et al.	703/13
X	B	US-6,534,954	03-2003	Plett, Gregory L.	320/132
X	C	US-6,515,454	02-2003	Schoch, Eberhard	320/132
X	D	US-6,208,949	03-2001	Eatwell, Graham P.	702/189
X	E	US-6,362,598	03-2002	Laig-Horstebrock et al.	320/132
X	F	US-6,441,586	08-2002	Tate et al.	320/132
X	G	US-6,300,763	10-2001	Kwok, Wellington Y.	324/427
X	H	US-6,307,351	10-2001	Yokoyama, Hidenori	320/132
X	I	US-6,359,419	03-2002	Verbrugge et al.	320/132
X	J	US-6,441,585	08-2002	Bertness, Kevin I.	320/132
X	K	US-6,453,249	09-2002	Shibutani et al.	702/63
X	L	US-6,011,379	01-2000	Singh et al.	320/132
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.